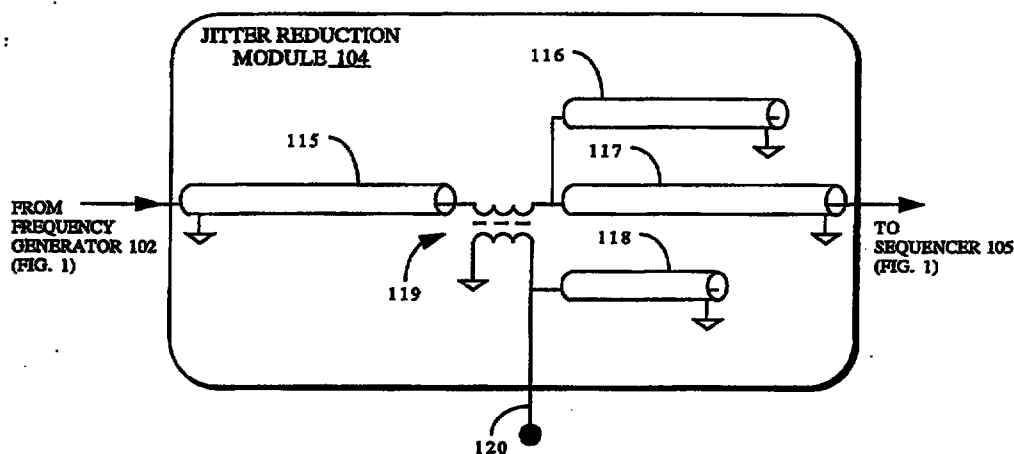




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(54) Title: JITTER REDUCTION MODULE**(57) Abstract**

Automatic test equipment having an apparatus for reducing jitter in a test system clock, including at least one transmission line for providing a delivery path for the test system clock, two tuning stubs for tuning the delivery path, and an RF transformer for providing a jitter output and electrically isolating the jitter output from the delivery path. The apparatus reduces jitter in the test system clock without substantially altering clock characteristics such as voltage levels, duty cycle, and overall shape of the test system clock.